

Լեզուների իմացություն

Հայերեն English Русский Українська

Հրատարակումներ

Հոդված

Analytics for AI Related Applications of Multidimensional Multitape Finite Automata

Samvel SHOUKOURIAN, Tigran GRIGORYAN, Sevak AMIRKHANYAN

Electronics, Communications and Networks 2023 49-60

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Functional Safety Compliant Test & Repair Framework for System-on-Chip Lifecycle Management

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

Mathematical Problems of Computer Science 2021 7-17

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Polynomial algorithm for equivalence problem of deterministic multitape finite automata

Samvel K. Shoukourian, Hayk A. Grigoryan

Theoretical Computer Science 2020 120-132

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Memory Physical Aware Multi-Level Fault Diagnosis Flow

SAMVEL SHOUKOURIAN, GURGEN HARUTYUNYAN, SUREN MARTIROSYAN, YERVANT ZORIAN

IEEE Transactions on Emerging Topics in Computing 2020 700-711

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Fault Awareness for Memory BIST Architecture Shaped by Multidimensional Prediction Mechanism

S. Shoukourian, G. Harutyunyan, Y. Zorian

IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2019 562-575

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Experimental study on Hamming and Hsiao Codes in the Context of Embedded Applications

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Automated Flow for Test Pattern Creation for IPs in SoC

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An Efficient Testing Methodology for Embedded Flash Memories

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Գիտաժողովի կյուբ

An efficient approach for memory repair by reducing the number of spares.

Vrezh Sargsyan, Valery A. Vardanian, Samvel K. Shoukourian, Yervant Zorian, Avetik Yessayan

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Extending fault periodicity table for testing faults in memories under 20nm.

Gurgen Harutyunyan, Samvel K. Shoukourian, Valery A. Vardanian, Yervant Zorian

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A power based memory BIST grouping methodology.

Lusine Martirosyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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Overview study on fault modeling and test methodology development for FinFET-based memories.

Grigor Tshagharyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

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Securing Test Infrastructure of System-on-Chips

S. Shoukourian, G.Tshagharyan, G.Harutyunyan, Y.Zorin

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Armenia: Communicating to World Community in Electronic Test and Design

Samvel Shoukourian, Yuri Shoukourian, Vladimir Sahakyan

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Testing Electronic Memories Based on Fault and Test Algorithm Periodicity

S. Shoukourian, G. Harutyunyan, V. Vardanian, A. Hakhumyan, Y. Zorian

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FINFET-BASED MEMORY TESTING USING MULTIPLE READ OPERATIONS

Samvel Shoukourian, Gurgen Harutyunyan, Grigor Tshagharyan, Yervant Zorian

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DETECTION OF ADDRESS ERRORS IN MEMORY DEVICES USING MULTI-SEGMENT ERROR DETECTION CODES

Samvel Shoukourian, Gurgen Harutyunyan, Hayk Grigoryan, Grigor Tshagharyan, Yervant Zorian
